

# H1J065F050

Silicon Carbide MOSFET  
N-CH E-MODE WITH JMOS™ TECHNOLOGY

## Features

- Monolithically integrated SiC MOSFET and JBS
- Low On-Resistance and High Current Density
- Low Capacitance for High Frequency Operation
- Ultra-high Avalanche Ruggedness
- Positive Temperature Coefficient Device
- RoHS Compliant and Halogen Free

## Benefits

- Low Build-in Diode  $V_F$  and  $Q_{rr}$
- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Light-weight Systems

## Applications

- Switching Mode Power Supply
- DC/DC Converters, UPS, and PFC
- EV Charging Station
- Motor Drives
- Power Inverters
- Solar/Wind Renewable Energy

## Absolute Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Drain – Source Voltage	$V_{DS, max}$	$V_{GS}=0V, I_{DS}=100\mu A$	650	V
Continuous Drain Current	$I_D$	$V_{GS}=20V, T_c=25^\circ\text{C}$	56	A
		$V_{GS}=20V, T_c=110^\circ\text{C}$	32.5	
Pulse Drain Current	$I_{D, pulse}$	$t_{PW}$ limitation per Fig.15	122	
Avalanche energy, Single Pulse	$E_{AS}$	$V_{DD}=100V, I_D=8.5A$	903	mJ
Power Dissipation	$P_D$	$T_c=25^\circ\text{C}$	208	W
Recommend Gate Source Voltage	$V_{GS, op}$	Static, recommended DC operating values	-5 to 20	V
Maximum Gate Source Voltage	$V_{GS, max}$	Transient operating limit (AC $f > 1\text{Hz}$ , duty cycle $< 1\%$ )	-10 to 25	
Junction & Storage Temperature	$T_j, T_{stg}$		-55 to 150	$^\circ\text{C}$
Soldering Temperature	$T_L$		260	
Mounting Torque	$M_D$	M3 or 6-32 screw	1.0	Nm

## Thermal Resistance

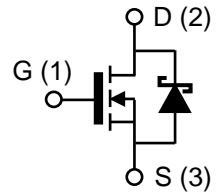
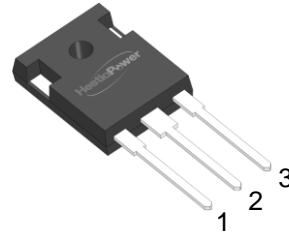
Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction to Case	$R_{\theta, JC}$		0.6		$^\circ\text{C/W}$
Thermal Resistance, Junction to Ambient	$R_{\theta, JA}$			40	$^\circ\text{C/W}$

## Product Summary

$V_{DS}$	650V
$I_D(@25^\circ\text{C})$	56A
$R_{DS(on)}$	50mΩ



## Circuit Diagram



Part Number	Package	Marking
H1J065F050	TO-247-3L	H1J065F050

## Description

The H1J065F050 650V, 50mΩ silicon carbide JMOS™ is an N-channel E-mode MOSFET with monolithically integrated JBS diode. Exploiting the outstanding wide bandgap material properties and JMOS™ technology, this device shows high power density and nice temp.-independent switching behavior. Thanks to JMOS™ technology, this device is free from BPD degradation and perform an excellent reverse recovery behavior. With an industry standard TO-247-3L package outline, this device allows designers to use conveniently.

**Electrical Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_{DS}=100\mu A$	650			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=10V, I_{DS}=10mA$		2.3		V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=650V, V_{GS}=0V$		<1	50	$\mu A$
		$V_{DS}=650V, V_{GS}=0V$ $T_j=150^\circ\text{C}$		10	500	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=20V, V_{DS}=0V$			250	nA
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=20V, I_{DS}=20A$		50	65	mΩ
		$V_{GS}=20V, I_{DS}=20A$ , $T_j=150^\circ\text{C}$		60		
Transconductance	$g_{fs}$	$V_{DS}=15V, I_{DS}=40A$		13.3		S
Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=400V$ $f=1MHz, V_{AC}=25mV$		1850		pF
Output Capacitance	$C_{oss}$			212		
Reverse Transfer Capacitance	$C_{rss}$			49		
Effective Output Capacitance, Energy Related	$C_{o(er)}$		$V_{GS}=0V$ , $V_{DS}=0$ to 400V		237	
Effective Output Capacitance, Time Related	$C_{o(tr)}$	$I_D=const.$ , $V_{GS}=0V$ , $V_{DS}=0$ to 400V		294		
Turn On Delay Time	$t_{d(on)}$	$V_{DS}=400V, V_{GS}=-4/+20V$ , $I_D=20A, R_L=20\Omega$ , $R_{G(ext)}=2.7\Omega$		16		ns
Rise Time	$t_r$			17		
Turn Off Delay Time	$t_{d(off)}$			20		
Fall Time	$t_f$			10		
$C_{oss}$ Stored Energy	$E_{oss}$	$V_{GS}=0V, V_{DS}=400V$ $f=1MHz, V_{AC}=25mV$		23.5		$\mu J$
Turn-on Switching Energy	$E_{on}$	$V_{DS}=400V, V_{GS}=0/20V$ , $I_D=20A$ ,		30*		
Turn-off Switching Energy	$E_{off}$	$R_{G(ext)}=2.7\Omega$		41*		
Internal Gate Resistance	$R_{G(int.)}$	$f=1MHz, V_{AC}=25mV$		1.2		Ω

\*Based on the results of calculation, note that the energy loss caused by the reverse recovery of free-wheeling diode is not included in  $E_{on}$ .

**Built-in SiC Diode Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Typ.	Unit
Inverse Diode Forward Voltage	$V_{SD}$	$V_{GS}=-5V, I_{SD}=10A$	2.35	V
Continuous Diode Forward Current	$I_S$	$V_{GS}=-5V, T_c=25^\circ\text{C}$	30	A
Reverse Recovery Time	$t_{rr}$	$V_{GS}=0V, T_j=150^\circ\text{C}$	59	ns
Reverse Recovery Charge	$Q_{rr}$	$I_{SD}=20A, V_{DS}=400V$ ,	116	nC
Peak Reverse Recovery Current	$I_{rrm}$	$di/dt=300A/\mu s$	3.4	A

**Gate Charge Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Value	Unit
Gate to Source Charge	$Q_{GS}$	$V_{DS}=400V$ , $V_{GS}=-5/+20V$ , $I_D=20A$	28	nC
Gate to Drain Charge	$Q_{GD}$		58	
Total Gate Charge	$Q_G$		125	
Gate plateau voltage	$V_{pl}$		8.5	V

## Typical Device Performance

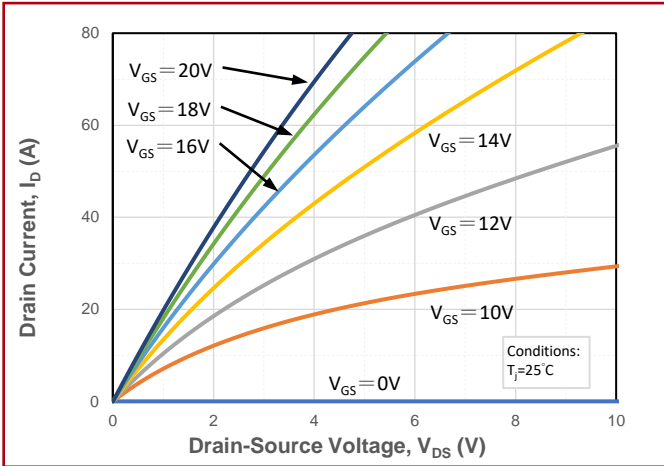


Fig.1 Forward Output Characteristics at  $T_j = 25^\circ\text{C}$

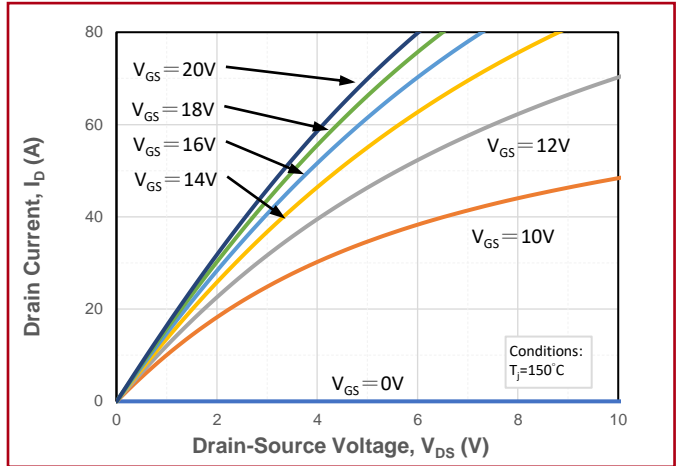


Fig.2 Forward Output Characteristics at  $T_j = 150^\circ\text{C}$

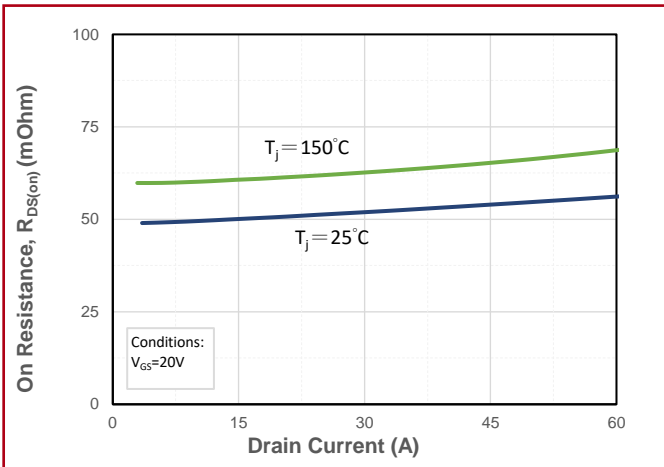


Fig.3 On-Resistance vs. Drain Current for Various  $T_j$

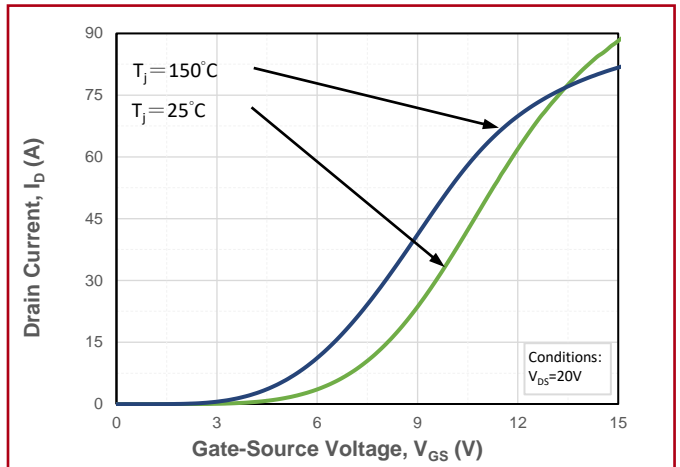


Fig.4 Transfer Characteristics for Various  $T_j$

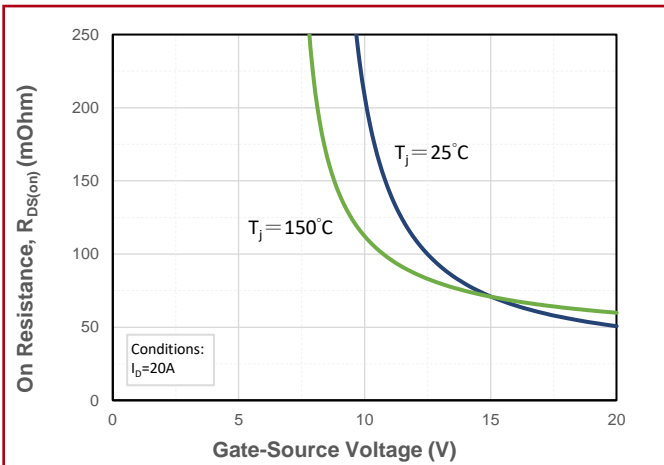


Fig.5 On-Resistance vs. Gate Voltage for Various  $T_j$

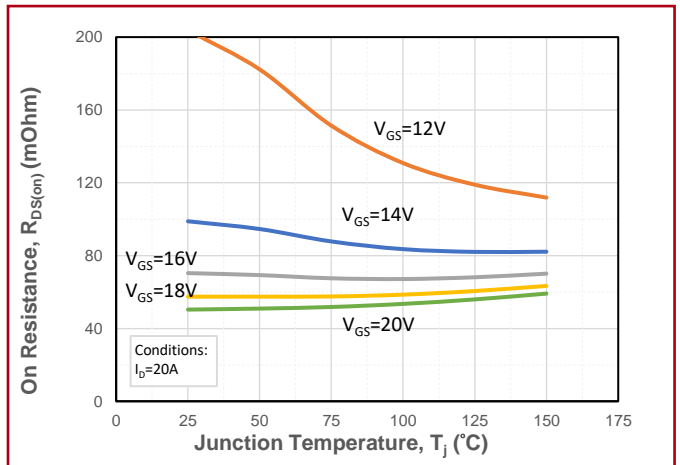
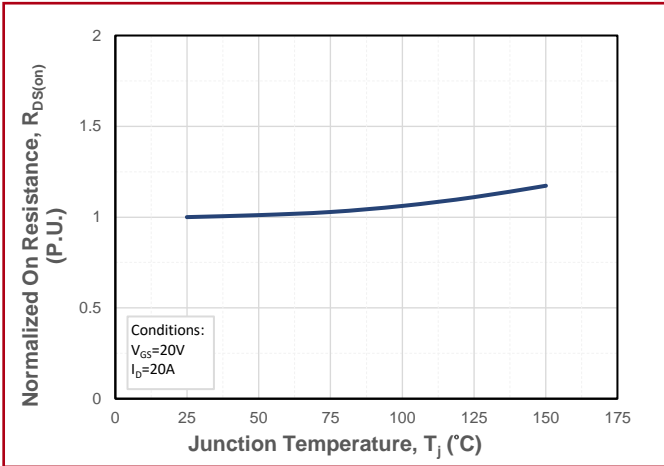
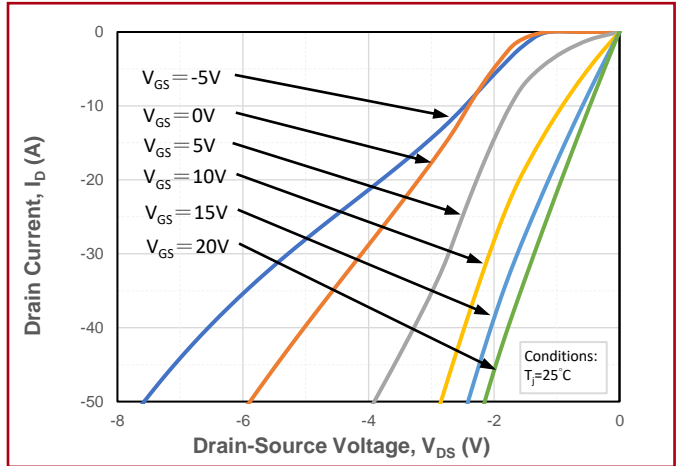


Fig.6 On-Resistance vs. Temperature for Various Gate Voltage

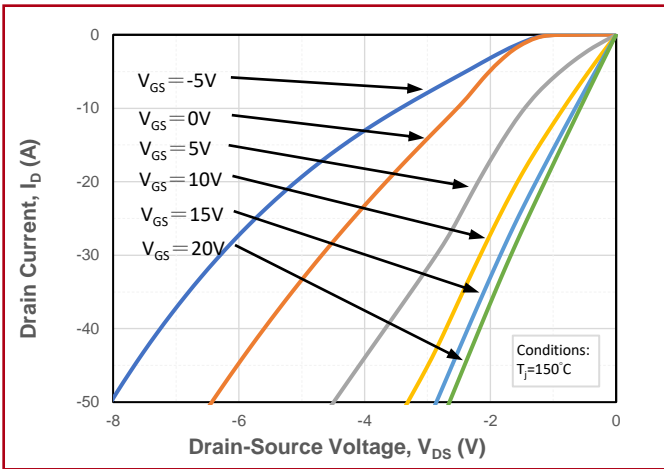
## Typical Device Performance



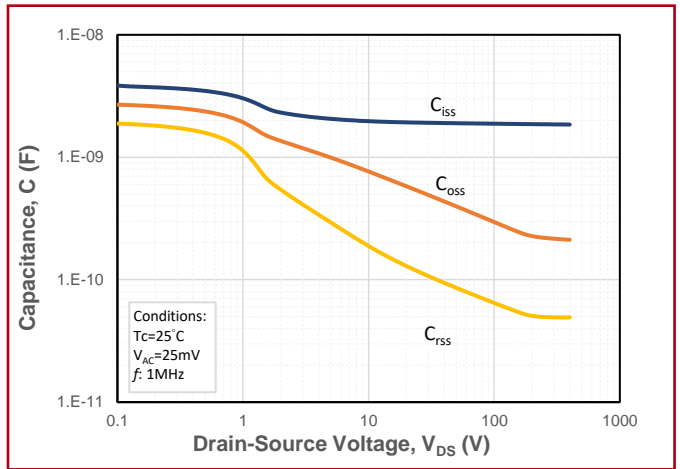
**Fig.7** Normalized On-Resistance vs. Temperature



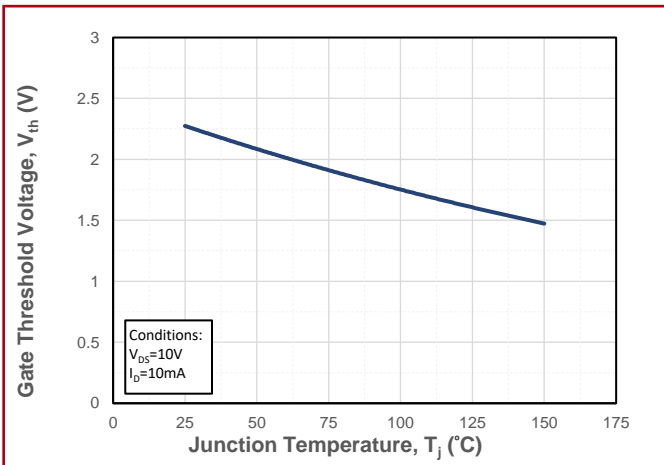
**Fig.8** Reverse Output Characteristics at  $T_j = 25^\circ C$



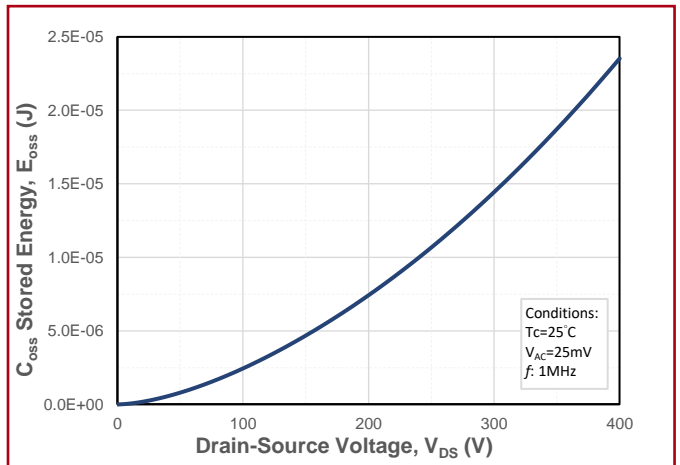
**Fig.9** Reverse Output Characteristics at  $T_j = 150^\circ C$



**Fig.10** Capacitances vs. Drain to Source Voltage

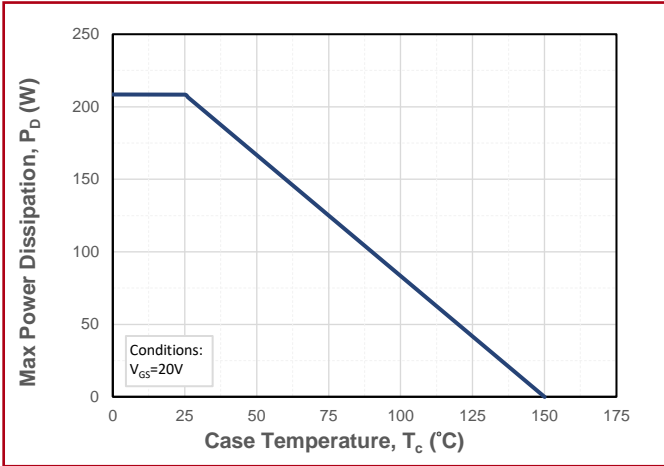


**Fig.11** Threshold Voltage vs. Temperature

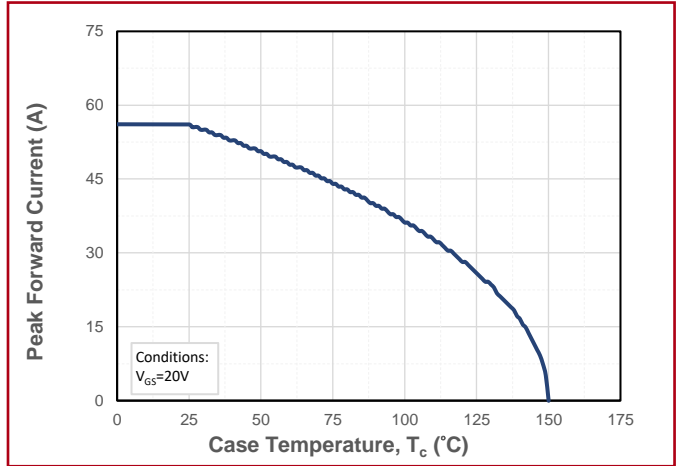


**Fig.12** Output Capacitor Stored Energy

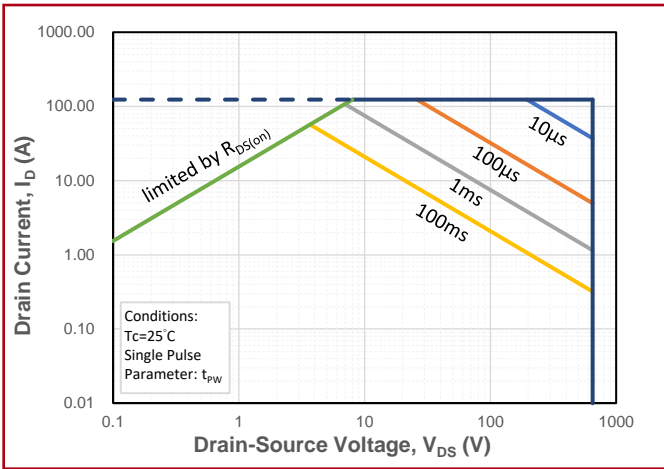
## Typical Device Performance



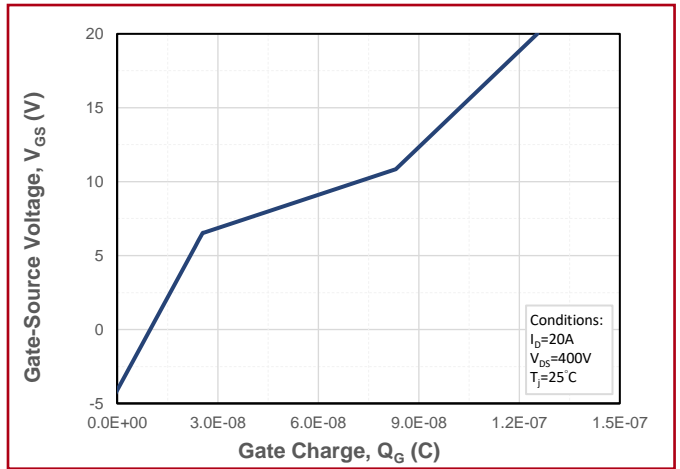
**Fig.13 Maximum Power Dissipation Derating vs. Case Temperature**



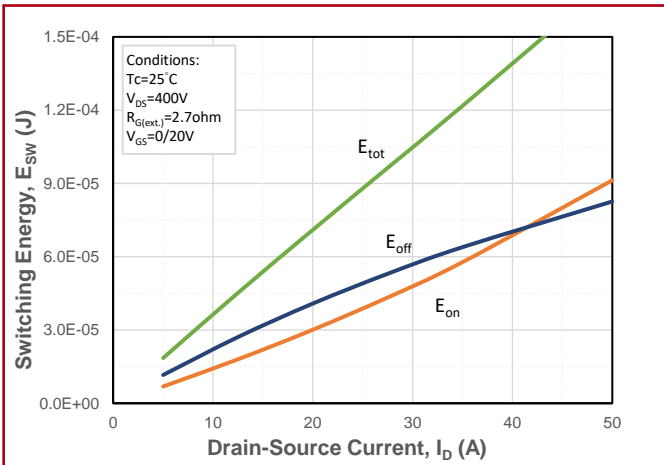
**Fig.14 Drain Current Derating vs. Case Temperature**



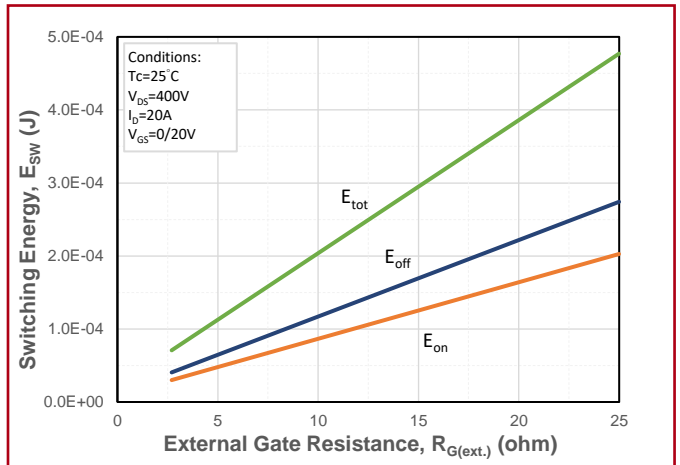
**Fig.15 Safe Operating Area**



**Fig.16 Gate Charge Characteristics**



**Fig.17 Clamped Inductive Switching Energy vs. Drain Current**



**Fig.18 Clamped Inductive Switching Energy vs. External Gate Resistor ( $R_{G(ext.)}$ )**

## Typical Device Performance

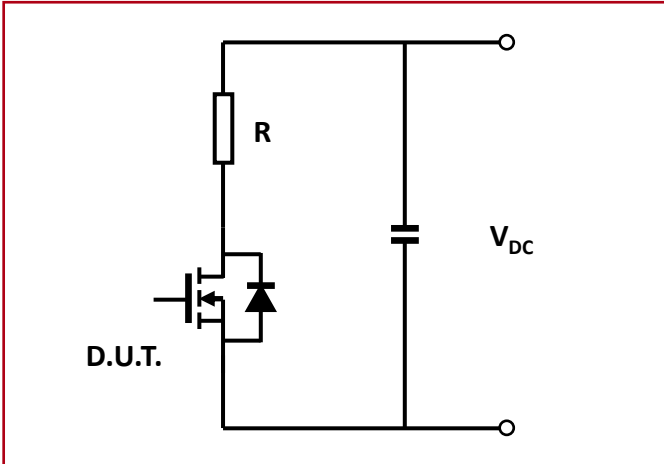


Fig.19 Schematic of Resistive Switching

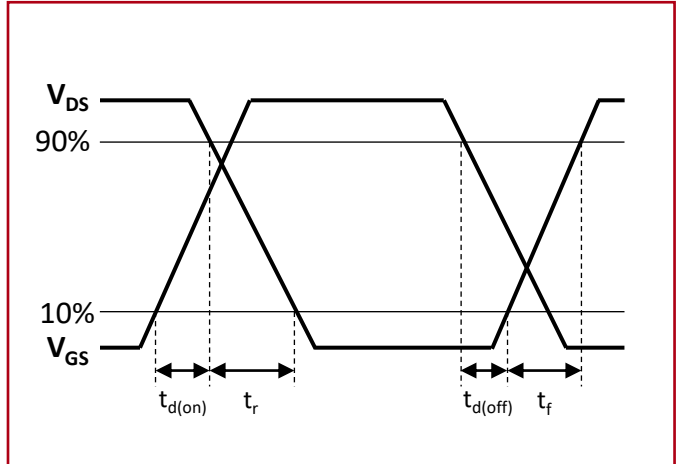


Fig.20 Switching Times Definition

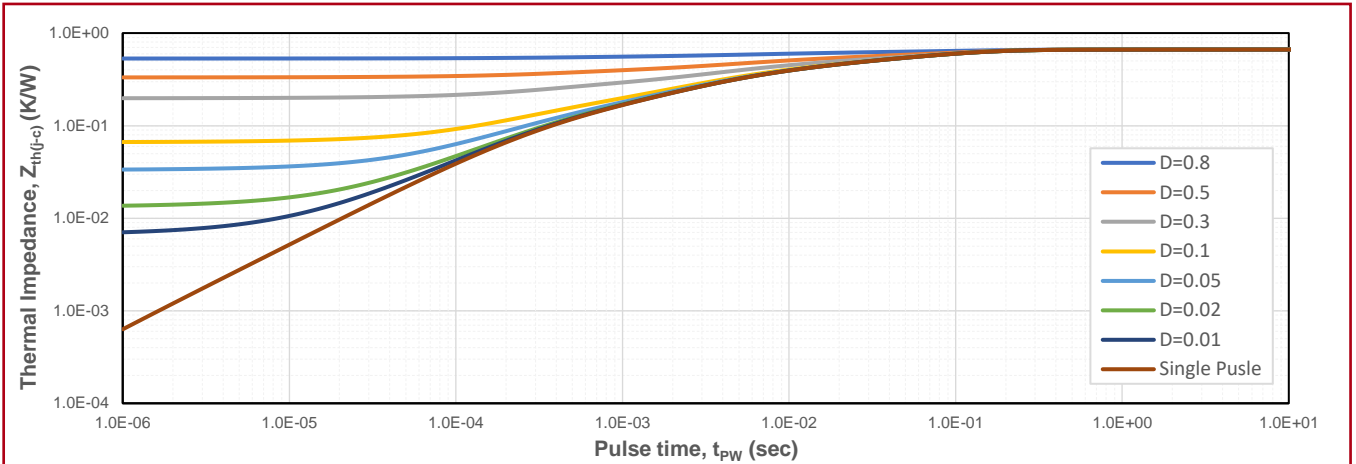


Fig.21 Transient Junction to Case Thermal Impedance

### Naming Rule

**H1 J 065 F 050**

#### Generation

H1 = Gen 1<sup>st</sup> Discrete

#### Device Type

M = MOSFET    J = JMOS

S = JBS diode

#### Breakdown Voltage

065 = 650V    170 = 1700V

120 = 1200V    330 = 3300V

#### Package

F = TO-247-3L    B = TO-220-3L

T = TO-263-2L    N = Bare Die

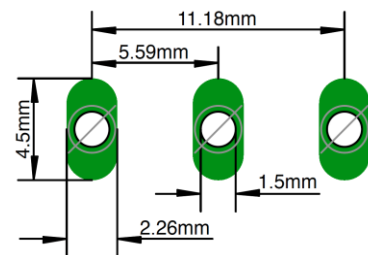
#### Typical On-Resistance

020 = 20mΩ    050 = 50mΩ    100 = 100mΩ

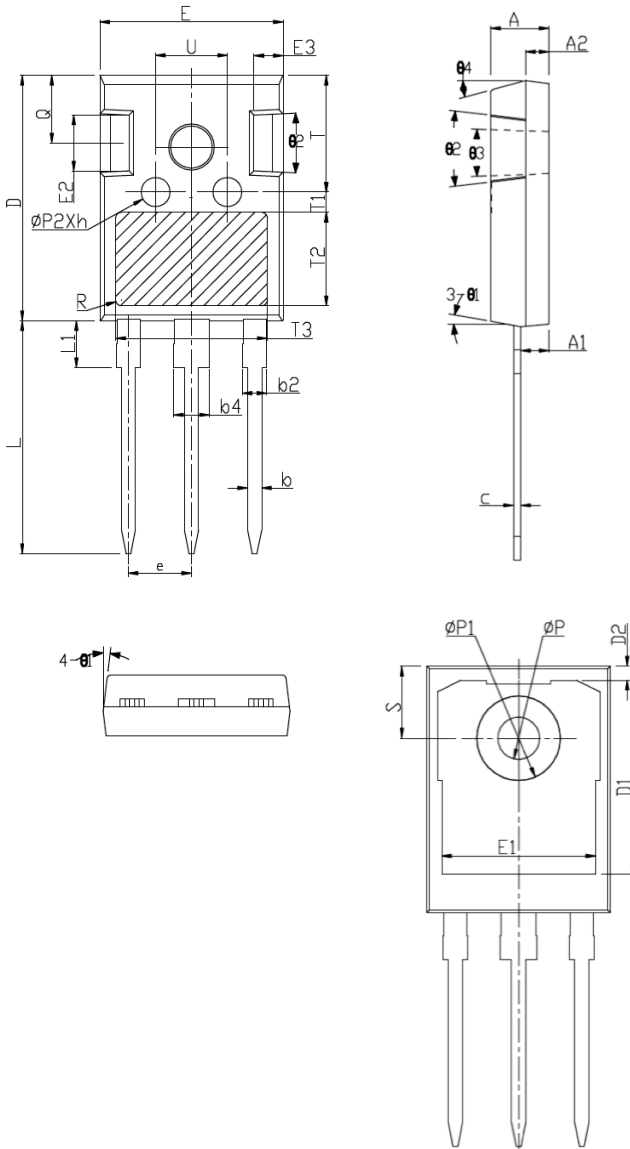
200 = 200mΩ

### Recommended Solder Pad Layout

#### TO-247-3L



## Package Dimensions



Symbol	mm		
	Min.	Typ.	Max.
A	4.75	5.00	5.25
A1	2.16	2.41	2.66
A2	1.85	2.00	2.15
b	1.11	1.21	1.35
b2	1.90	2.01	2.25
b4	2.90	3.01	3.25
c	0.51	0.61	0.75
D	20.60	21.00	21.40
D1	16.15	16.55	16.95
D2	1.00	1.20	1.40
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.70	5.00	5.30
E3	2.25	2.50	2.75
e	5.44 BSC		
h	0.00	0.10	0.25
L	19.52	19.92	20.32
L1	-	-	4.30
ØP	3.35	3.60	3.85
ØP1	-	-	7.30
ØP2	2.25	2.50	2.75
Q	5.50	5.80	6.10
S	6.15 BSC		
R	0.50 REF		
T	9.70	-	10.30
T1	1.65 REF		
T2	8.00 REF		
T3	12.80 REF		
U	5.90	-	6.50
Ø1	4°	7°	10°
Ø2	2°	5°	8°
Ø3	1°	-	2°
Ø4	10°	15°	20°

## Notes

- The information provided herein is subject to change without notice.
- For other information that does not show on this datasheet, please contact us for inquiry.